Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/657,151	SEKI ET AL.	
Examiner	Art Unit	
Toan Ton	2871	

	SEARCHED		
Class	Subclass	Date	Examiner
349	42-43	3/7/2005	TTON
	113		
	,		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	1		
	-		

SEARCH (INCLUDING SEAR		)
	DATE	EXMR
EAST thin film transistor pixel contact hole/opening reflect\$ diffus\$, scatter\$ interlayer\$ insulat\$ recess\$, protrusion	3/7/2005	TTON
		,
· · · · · · · · · · · · · · · · · · ·		: